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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	100MHz
Connectivity	I²C, IrDA, SPI, UART/USART, USB, USB OTG
Peripherals	DMA, I²S, LVD, POR, PWM, WDT
Number of I/O	66
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	24K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 33x16b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mk22fn128vll10

1 Ratings

1.1 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T_{STG}	Storage temperature	-55	150	°C	1
T_{SDR}	Solder temperature, lead-free	—	260	°C	2

1. Determined according to JEDEC Standard JESD22-A103, *High Temperature Storage Life*.
2. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

1.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

1.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V_{HBM}	Electrostatic discharge voltage, human body model	-2000	+2000	V	1
V_{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	2
I_{LAT}	Latch-up current at ambient temperature of 105°C	-100	+100	mA	3

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
2. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.
3. Determined according to JEDEC Standard JESD78, *IC Latch-Up Test*.

1.4 Voltage and current operating ratings

Symbol	Description	Min.	Max.	Unit
USBV _{DD}	USB Transceiver supply voltage	-0.3	3.8	V
V _{DD}	Digital supply voltage	-0.3	3.8	V
I _{DD}	Digital supply current	—	145	mA
V _{DIO}	Digital input voltage	-0.3	V _{DD} + 0.3	V
V _{AIO}	Analog ¹	-0.3	V _{DD} + 0.3	V
I _D	Maximum current single pin limit (applies to all digital pins)	-25	25	mA
V _{DDA}	Analog supply voltage	V _{DD} - 0.3	V _{DD} + 0.3	V
V _{USB0_DP}	USB0_DP input voltage	-0.3	3.63	V
V _{USB0_DM}	USB0_DM input voltage	-0.3	3.63	V
V _{BAT}	RTC battery supply voltage	-0.3	3.8	V

1. Analog pins are defined as pins that do not have an associated general purpose I/O port function.

2 General

2.1 AC electrical characteristics

Unless otherwise specified, propagation delays are measured from the 50% to the 50% point, and rise and fall times are measured at the 20% and 80% points, as shown in the following figure.

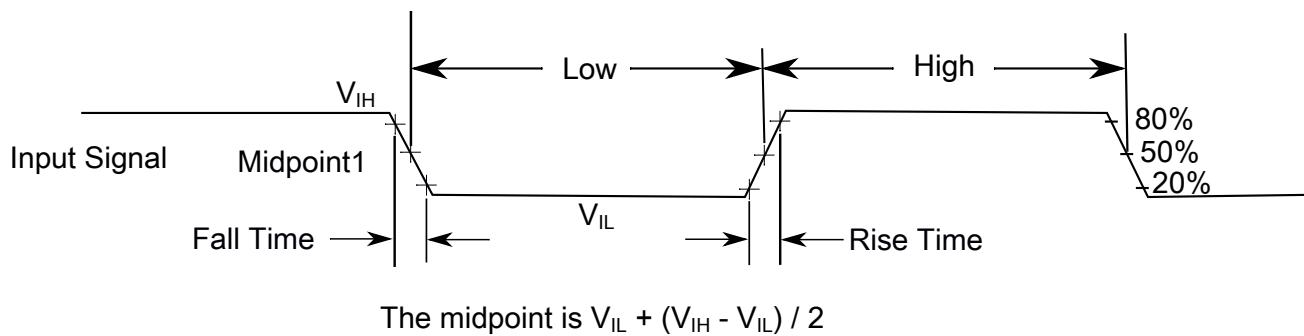


Figure 2. Input signal measurement reference

2.2 Nonswitching electrical specifications

Table 5. Power mode transition operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t _{POR}	After a POR event, amount of time from the point V _{DD} reaches 1.71 V to execution of the first instruction across the operating temperature range of the chip.	—	—	300	μs	1
	• VLLS0 → RUN	—	—	135	μs	
	• VLLS1 → RUN	—	—	135	μs	
	• VLLS2 → RUN	—	—	75	μs	
	• VLLS3 → RUN	—	—	75	μs	
	• LLS2 → RUN	—	—	6	μs	
	• LLS3 → RUN	—	—	6	μs	
	• VLPS → RUN	—	—	5.7	μs	
	• STOP → RUN	—	—	5.7	μs	

1. Normal boot (FTFA_OPT[LPBOOT]=1)

2.2.5 Power consumption operating behaviors

The current parameters in the table below are derived from code executing a while(1) loop from flash, unless otherwise noted.

The IDD typical values represent the statistical mean at 25°C, and the IDD maximum values for RUN, WAIT, VLPR, and VLPW represent data collected at 125°C junction temperature unless otherwise noted. The maximum values represent characterized results equivalent to the mean plus three times the standard deviation (mean + 3 sigma).

Table 6. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DDA}	Analog supply current	—	—	See note	mA	1
I _{DD_HSRUN}	High Speed Run mode current - all peripheral clocks disabled, CoreMark benchmark code executing from flash					

Table continues on the next page...

Table 6. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	@ 1.8V @ 3.0V	— —	19.51 19.51	20.24 20.24	mA mA	2 , 3 , 4
I _{DD_HSRUN}	High Speed Run mode current - all peripheral clocks disabled, code executing from flash @ 1.8V @ 3.0V					5
I _{DD_HSRUN}	High Speed Run mode current — all peripheral clocks enabled, code executing from flash @ 1.8V @ 3.0V					6
I _{DD_RUN}	Run mode current in Compute operation — CoreMark benchmark code executing from flash @ 1.8V @ 3.0V		11.39 11.58	12.12 12.31	mA mA	2 , 3 , 7
I _{DD_RUN}	Run mode current in Compute operation — code executing from flash @ 1.8V @ 3.0V		10.90 10.90	11.90 12.23	mA mA	7
I _{DD_RUN}	Run mode current — all peripheral clocks disabled, code executing from flash @ 1.8V @ 3.0V					8
I _{DD_RUN}	Run mode current — all peripheral clocks enabled, code executing from flash @ 1.8V @ 3.0V • @ 25°C • @ 70°C • @ 85°C • @ 105°C		15.5 15.6 15.6 15.6 16.3	16.23 16.33 16.33 16.33 17.03	mA mA mA mA mA	9
I _{DD_RUN}	Run mode current — Compute operation, code executing from flash @ 1.8V @ 3.0V • @ 25°C • @ 70°C • @ 85°C • @ 105°C		10.9 10.9 10.9 11.5	11.63 11.63 11.63 12.23	mA mA mA mA	10

Table continues on the next page...

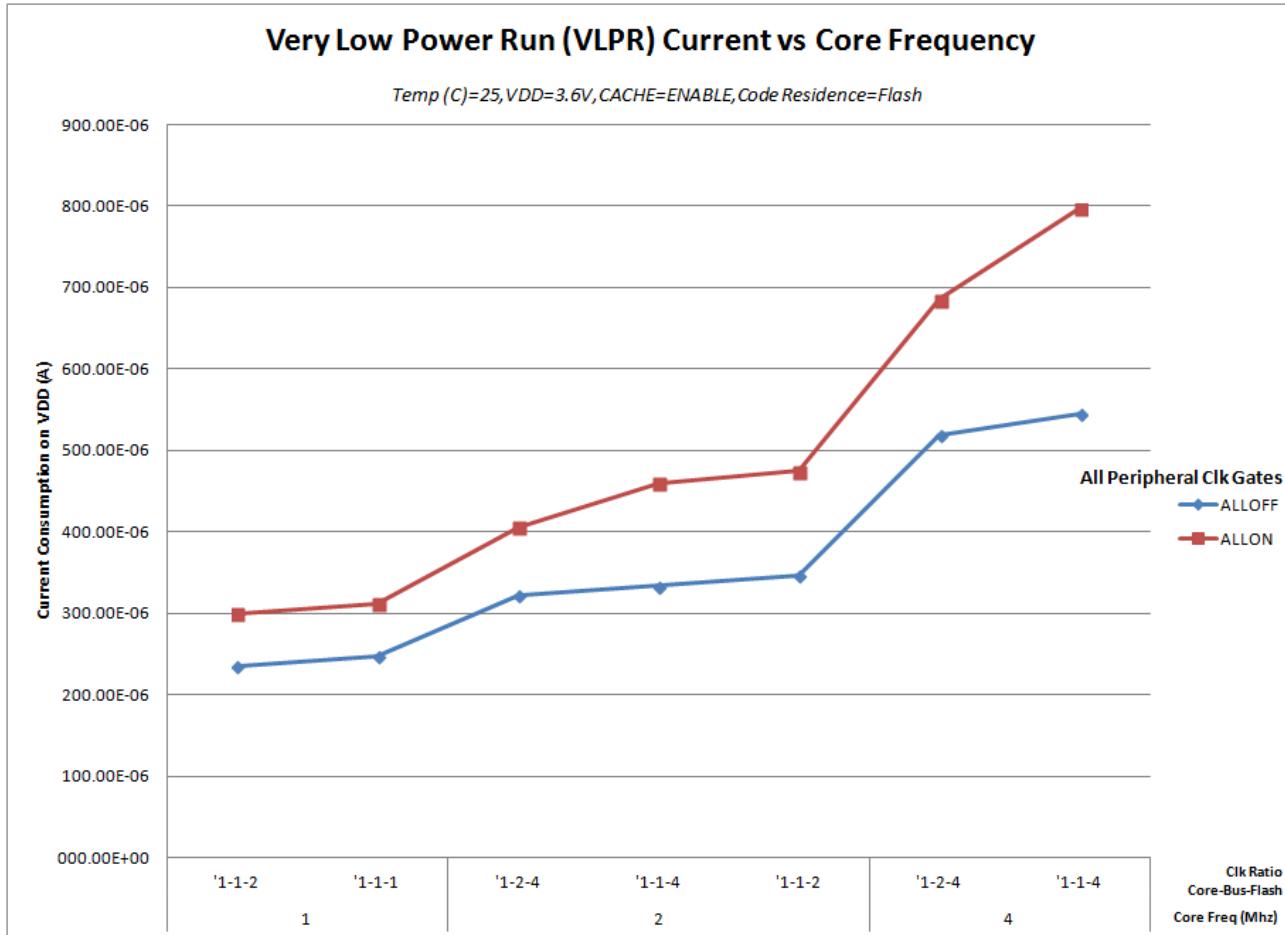


Figure 4. VLPR mode supply current vs. core frequency

2.2.6 EMC radiated emissions operating behaviors

Table 8. EMC radiated emissions operating behaviors for 64 LQFP package

Parameter	Conditions	Clocks	Frequency range	Level (Typ.)	Unit	Notes
V_{EME}	Device configuration, test conditions and EM testing per standard IEC 61967-2. Supply voltages: Temp = 25°C	FSYS = 100 MHz FBUS = 50 MHz External crystal = 10 MHz	150 kHz–50 MHz	13	dBuV	1, 2, 3
			50 MHz–150 MHz	24		
			150 MHz–500 MHz	23		
			500 MHz–1000 MHz	7		
			IEC level	L		4

1. Measurements were made per IEC 61967-2 while the device was running typical application code.
2. Measurements were performed on the 64LQFP device, MK22FN128VLH10 .
3. The reported emission level is the value of the maximum measured emission, rounded up to the next whole number, from among the measured orientations in each frequency range.
4. IEC Level Maximums: M \leq 18dBmV, L \leq 24dBmV, K \leq 30dBmV, I \leq 36dBmV, H \leq 42dBmV .

2.4 Thermal specifications

2.4.1 Thermal operating requirements

Table 12. Thermal operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
T _J	Die junction temperature	-40	125	°C	
T _A	Ambient temperature	-40	105	°C	1

1. Maximum T_A can be exceeded only if the user ensures that T_J does not exceed maximum T_J. The simplest method to determine T_J is: T_J = T_A + R_{θJA} × chip power dissipation.

2.4.2 Thermal attributes

Board type	Symbol	Description	121 XFBGA	100 LQFP	64 LQFP	64 MAPBGA	Unit	Notes
Single-layer (1s)	R _{θJA}	Thermal resistance, junction to ambient (natural convection)	46.6	63	69	53.8	°C/W	1
Four-layer (2s2p)	R _{θJA}	Thermal resistance, junction to ambient (natural convection)	39.3	50	51	46.0	°C/W	2
Single-layer (1s)	R _{θJMA}	Thermal resistance, junction to ambient (200 ft./min. air speed)	39.0	53	57	45.8	°C/W	3
Four-layer (2s2p)	R _{θJMA}	Thermal resistance, junction to ambient (200 ft./min. air speed)	35.3	44	44	41.0	°C/W	3
—	R _{θJB}	Thermal resistance, junction to board	36.7	36	33	43.4	°C/W	4

Table continues on the next page...

Table 16. MCG specifications (continued)

Symbol	Description		Min.	Typ.	Max.	Unit	Notes
		2197 × $f_{\text{fll_ref}}$					
		High range (DRS=11)	—	95.98	—	MHz	
		2929 × $f_{\text{fll_ref}}$					
$J_{\text{cyc_fll}}$	FLL period jitter		—	—	—	ps	
	• $f_{\text{VCO}} = 48 \text{ MHz}$		—	180	—		
	• $f_{\text{VCO}} = 98 \text{ MHz}$			150			
$t_{\text{fll_acquire}}$	FLL target frequency acquisition time	—	—	1	ms		7

1. This parameter is measured with the internal reference (slow clock) being used as a reference to the FLL (FEI clock mode).
2. $2.0 \text{ V} \leq \text{VDD} \leq 3.6 \text{ V}$.
3. These typical values listed are with the slow internal reference clock (FEI) using factory trim and DMX32=0.
4. The resulting system clock frequencies should not exceed their maximum specified values. The DCO frequency deviation ($\Delta f_{\text{dco_t}}$) over voltage and temperature should be considered.
5. These typical values listed are with the slow internal reference clock (FEI) using factory trim and DMX32=1.
6. The resulting clock frequency must not exceed the maximum specified clock frequency of the device.
7. This specification applies to any time the FLL reference source or reference divider is changed, trim value is changed, DMX32 bit is changed, DRS bits are changed, or changing from FLL disabled (BLPE, BLPI) to FLL enabled (FEI, FEE, FBE, FBI). If a crystal/resonator is being used as the reference, this specification assumes it is already running.

3.3.2 IRC48M specifications

Table 17. IRC48M specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{DD}	Supply voltage	1.71	—	3.6	V	
I_{DD48M}	Supply current	—	400	500	μA	
f_{irc48m}	Internal reference frequency	—	48	—	MHz	
$\Delta f_{\text{irc48m_ol_hv}}$	Open loop total deviation of IRC48M frequency at high voltage (VDD=1.89V-3.6V) over 0°C to 70°C	—				1
	Regulator enable (USB_CLK_RECOVER_IRC_EN[REG_EN]=1)	—	± 0.2	± 0.5	% f_{irc48m}	
$\Delta f_{\text{irc48m_ol_hv}}$	Open loop total deviation of IRC48M frequency at high voltage (VDD=1.89V-3.6V) over full temperature	—				1
	Regulator enable (USB_CLK_RECOVER_IRC_EN[REG_EN]=1)	—	± 0.4	± 1.0	% f_{irc48m}	
$\Delta f_{\text{irc48m_ol_lv}}$	Open loop total deviation of IRC48M frequency at low voltage (VDD=1.71V-1.89V) over full temperature	—				1
	Regulator disable (USB_CLK_RECOVER_IRC_EN[REG_EN]=0)	—	± 0.4	± 1.0	% f_{irc48m}	
	Regulator enable (USB_CLK_RECOVER_IRC_EN[REG_EN]=1)	—	± 0.5	± 1.5		

Table continues on the next page...

Table 18. Oscillator DC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
C_y	XTAL load capacitance	—	—	—		2, 3
R_F	Feedback resistor — low-frequency, low-power mode (HGO=0)	—	—	—	$M\Omega$	2, 4
	Feedback resistor — low-frequency, high-gain mode (HGO=1)	—	10	—	$M\Omega$	
	Feedback resistor — high-frequency, low-power mode (HGO=0)	—	—	—	$M\Omega$	
	Feedback resistor — high-frequency, high-gain mode (HGO=1)	—	1	—	$M\Omega$	
R_S	Series resistor — low-frequency, low-power mode (HGO=0)	—	—	—	$k\Omega$	
	Series resistor — low-frequency, high-gain mode (HGO=1)	—	200	—	$k\Omega$	
	Series resistor — high-frequency, low-power mode (HGO=0)	—	—	—	$k\Omega$	
	Series resistor — high-frequency, high-gain mode (HGO=1)	—	0	—	$k\Omega$	
V_{pp}^5	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, low-power mode (HGO=0)	—	0.6	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, high-gain mode (HGO=1)	—	V_{DD}	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, low-power mode (HGO=0)	—	0.6	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, high-gain mode (HGO=1)	—	V_{DD}	—	V	

1. $V_{DD}=3.3$ V, Temperature =25 °C
2. See crystal or resonator manufacturer's recommendation
3. C_x and C_y can be provided by using either integrated capacitors or external components.
4. When low-power mode is selected, R_F is integrated and must not be attached externally.
5. The EXTAL and XTAL pins should only be connected to required oscillator components and must not be connected to any other device.

3.3.3.2 Oscillator frequency specifications

Table 19. Oscillator frequency specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{osc_lo}	Oscillator crystal or resonator frequency — low-frequency mode (MCG_C2[RANGE]=00)	32	—	40	kHz	

Table continues on the next page...

3.6.3.2 12-bit DAC operating behaviors

Table 31. 12-bit DAC operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DDA_DACL_P}	Supply current — low-power mode	—	—	330	µA	
I _{DDA_DACH_P}	Supply current — high-speed mode	—	—	1200	µA	
t _{DACLP}	Full-scale settling time (0x080 to 0xF7F) — low-power mode	—	100	200	µs	1
t _{DACHP}	Full-scale settling time (0x080 to 0xF7F) — high-power mode	—	15	30	µs	1
t _{CCDACL_P}	Code-to-code settling time (0xBF8 to 0xC08) — low-power mode and high-speed mode	—	0.7	1	µs	1
V _{dacoutl}	DAC output voltage range low — high-speed mode, no load, DAC set to 0x000	—	—	100	mV	
V _{dacouth}	DAC output voltage range high — high-speed mode, no load, DAC set to 0xFFFF	V _{DACR} –100	—	V _{DACR}	mV	
INL	Integral non-linearity error — high speed mode	—	—	±8	LSB	2
DNL	Differential non-linearity error — V _{DACR} > 2 V	—	—	±1	LSB	3
DNL	Differential non-linearity error — V _{DACR} = VREF_OUT	—	—	±1	LSB	4
V _{OFFSET}	Offset error	—	±0.4	±0.8	%FSR	5
E _G	Gain error	—	±0.1	±0.6	%FSR	5
PSRR	Power supply rejection ratio, V _{DDA} ≥ 2.4 V	60	—	90	dB	
T _{CO}	Temperature coefficient offset voltage	—	3.7	—	µV/C	6
T _{GE}	Temperature coefficient gain error	—	0.000421	—	%FSR/C	
R _{op}	Output resistance (load = 3 kΩ)	—	—	250	Ω	
SR	Slew rate -80h → F7Fh → 80h <ul style="list-style-type: none"> • High power (SP_{HP}) • Low power (SP_{LP}) 	1.2 0.05	1.7 0.12	—	V/µs	
BW	3dB bandwidth <ul style="list-style-type: none"> • High power (SP_{HP}) • Low power (SP_{LP}) 	550 40	— —	— —	kHz	

- Settling within ±1 LSB
- The INL is measured for 0 + 100 mV to V_{DACR} –100 mV
- The DNL is measured for 0 + 100 mV to V_{DACR} –100 mV
- The DNL is measured for 0 + 100 mV to V_{DACR} –100 mV with V_{DDA} > 2.4 V
- Calculated by a best fit curve from V_{SS} + 100 mV to V_{DACR} –100 mV
- V_{DDA} = 3.0 V, reference select set for V_{DDA} (DACx_CO:DACRFS = 1), high power mode (DACx_C0:LPEN = 0), DAC set to 0x800, temperature range is across the full range of the device

3.8.1 USB electrical specifications

The USB electorials for the USB On-the-Go module conform to the standards documented by the Universal Serial Bus Implementers Forum. For the most up-to-date standards, visit usb.org.

NOTE

The MCGFLLCLK does not meet the USB jitter or signaling rate specifications for certification.

The IRC48M meets the USB jitter and signaling rate specifications for certification in Device mode when the USB clock recovery mode is enabled. It does not meet the USB signaling rate specifications for certification in Host mode operation.

3.8.2 DSPI switching specifications (limited voltage range)

The Deserial Serial Peripheral Interface (DSPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The tables below provide DSPI timing characteristics for classic SPI timing modes. Refer to the SPI chapter of the Reference Manual for information on the modified transfer formats used for communicating with slower peripheral devices.

Table 36. Master mode DSPI timing (limited voltage range)

Num	Description	Min.	Max.	Unit	Notes
	Operating voltage	2.7	3.6	V	
	Frequency of operation	—	25	MHz	
DS1	DSPI_SCK output cycle time	$2 \times t_{BUS}$	—	ns	
DS2	DSPI_SCK output high/low time	$(t_{SCK}/2) - 2$	$(t_{SCK}/2) + 2$	ns	
DS3	DSPI_PCSn valid to DSPI_SCK delay	$(t_{BUS} \times 2) - 2$	—	ns	1
DS4	DSPI_SCK to DSPI_PCSn invalid delay	$(t_{BUS} \times 2) - 2$	—	ns	2
DS5	DSPI_SCK to DSPI_SOUT valid	—	8.5	ns	
DS6	DSPI_SCK to DSPI_SOUT invalid	-2	—	ns	
DS7	DSPI_SIN to DSPI_SCK input setup	16.2	—	ns	
DS8	DSPI_SCK to DSPI_SIN input hold	0	—	ns	

1. The delay is programmable in SPIx_CTARn[PSSCK] and SPIx_CTARn[CSSCK].

Peripheral operating requirements and behaviors

2. The delay is programmable in SPIx_CTARn[PASC] and SPIx_CTARn[ASC].

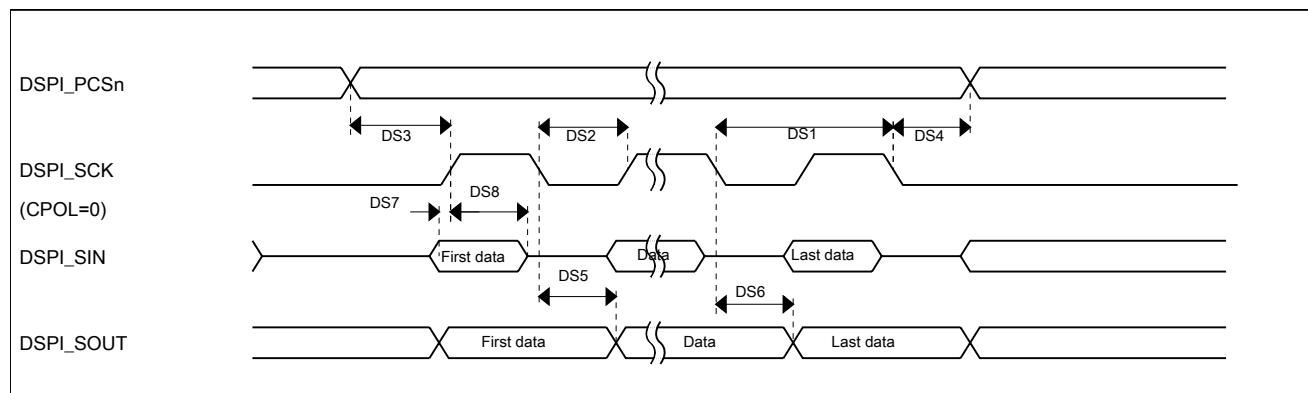


Figure 19. DSPI classic SPI timing — master mode

Table 37. Slave mode DSPI timing (limited voltage range)

Num	Description	Min.	Max.	Unit	Notes
	Operating voltage	2.7	3.6	V	
	Frequency of operation	—	12.5	MHz	1
DS9	DSPI_SCK input cycle time	$4 \times t_{BUS}$	—	ns	
DS10	DSPI_SCK input high/low time	$(t_{SCK}/2) - 2$	$(t_{SCK}/2) + 2$	ns	
DS11	DSPI_SCK to DSPI_SOUT valid	—	21.4	ns	
DS12	DSPI_SCK to DSPI_SOUT invalid	0	—	ns	
DS13	DSPI_SIN to DSPI_SCK input setup	2.6	—	ns	
DS14	DSPI_SCK to DSPI_SIN input hold	7	—	ns	
DS15	DSPI_SS active to DSPI_SOUT driven	—	17	ns	
DS16	DSPI_SS inactive to DSPI_SOUT not driven	—	17	ns	

1. The maximum operating frequency is measured with noncontinuous CS and SCK. When DSPI is configured with continuous CS and SCK, the SPI clock must not be greater than 1/6 of the bus clock. For example, when the bus clock is 60 MHz, the SPI clock must not be greater than 10 MHz.

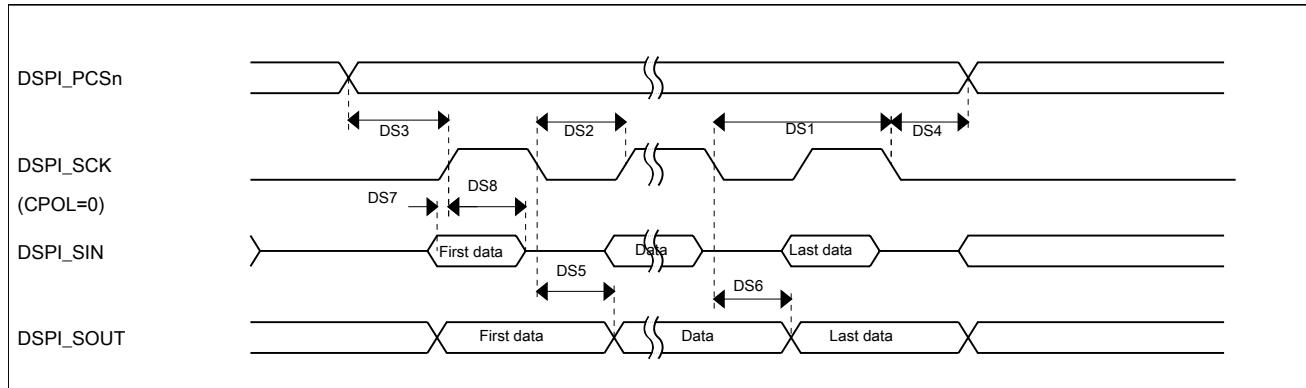


Figure 21. DSPI classic SPI timing — master mode

Table 39. Slave mode DSPI timing (full voltage range)

Num	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
	Frequency of operation	—	6.25	MHz
DS9	DSPI_SCK input cycle time	$8 \times t_{BUS}$	—	ns
DS10	DSPI_SCK input high/low time	$(t_{SCK}/2) - 4$	$(t_{SCK}/2) + 4$	ns
DS11	DSPI_SCK to DSPI_SOUT valid	—	29.5	ns
DS12	DSPI_SCK to DSPI_SOUT invalid	0	—	ns
DS13	DSPI_SIN to DSPI_SCK input setup	3.2	—	ns
DS14	DSPI_SCK to DSPI_SIN input hold	7	—	ns
DS15	DSPI_SS active to DSPI_SOUT driven	—	25	ns
DS16	DSPI_SS inactive to DSPI_SOUT not driven	—	25	ns

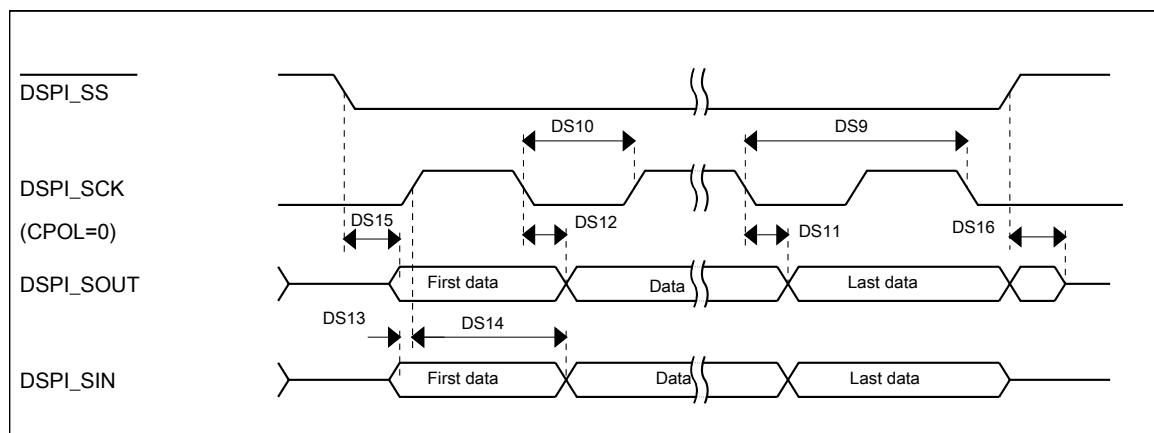
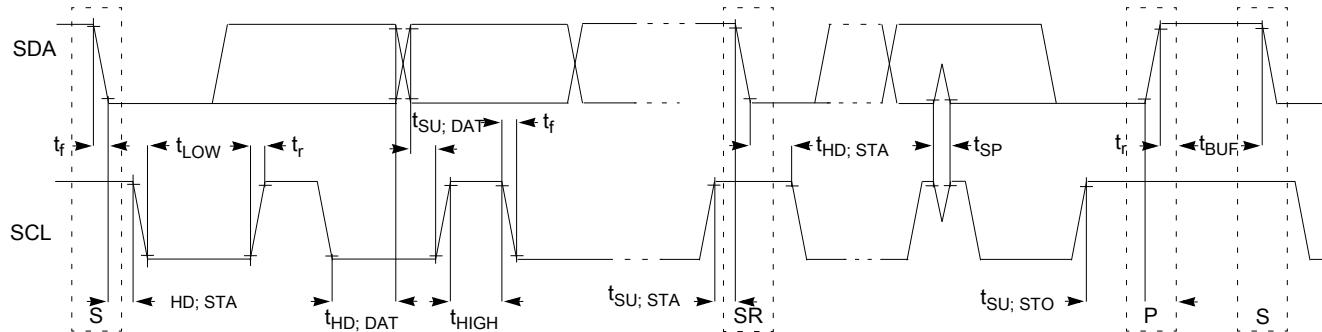


Figure 22. DSPI classic SPI timing — slave mode

Table 41. I²C 1 Mbps timing (continued)

Characteristic	Symbol	Minimum	Maximum	Unit
Data set-up time	$t_{SU; DAT}$	50	—	ns
Rise time of SDA and SCL signals	t_r	$20 + 0.1C_b^2$	120	ns
Fall time of SDA and SCL signals	t_f	$20 + 0.1C_b^2$	120	ns
Set-up time for STOP condition	$t_{SU; STO}$	0.26	—	μs
Bus free time between STOP and START condition	t_{BUF}	0.5	—	μs
Pulse width of spikes that must be suppressed by the input filter	t_{SP}	0	50	ns

1. The maximum SCL clock frequency of 1 Mbps can support maximum bus loading when using the High drive pins across the full voltage range.
2. C_b = total capacitance of the one bus line in pF.

**Figure 23. Timing definition for devices on the I²C bus**

3.8.5 UART switching specifications

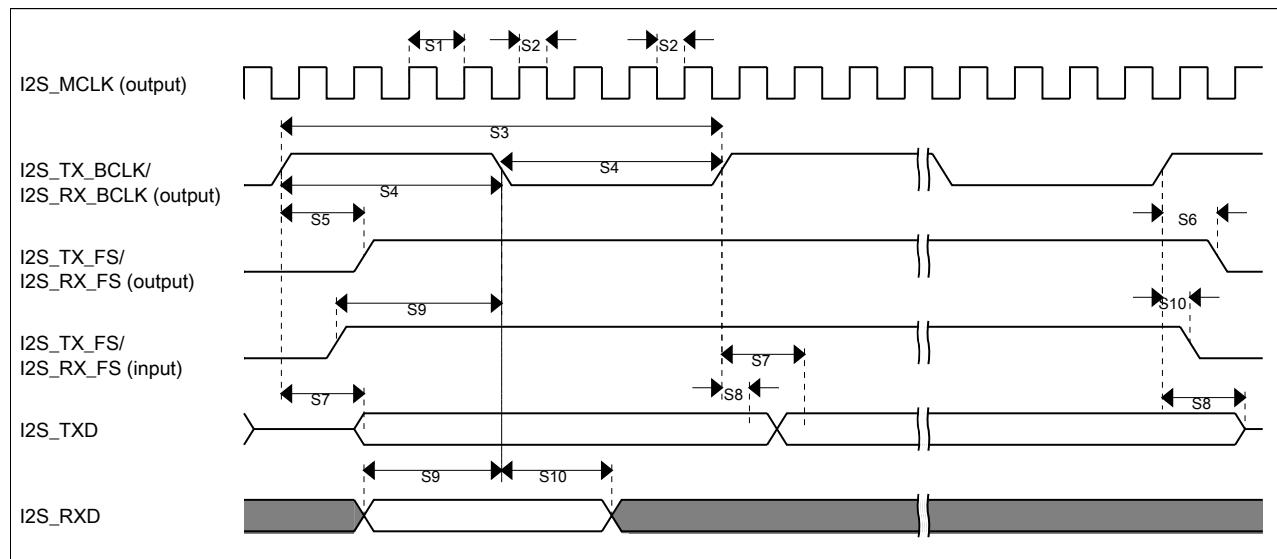
See [General switching specifications](#).

3.8.6 I2S/SAI switching specifications

This section provides the AC timing for the I2S/SAI module in master mode (clocks are driven) and slave mode (clocks are input). All timing is given for noninverted serial clock polarity (TCR2[BCP] is 0, RCR2[BCP] is 0) and a noninverted frame sync (TCR4[FSP] is 0, RCR4[FSP] is 0). If the polarity of the clock and/or the frame sync have been inverted, all the timing remains valid by inverting the bit clock signal (BCLK) and/or the frame sync (FS) signal shown in the following figures.

Table 44. I2S/SAI master mode timing in Normal Run, Wait and Stop modes (full voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time	40	—	ns
S2	I2S_MCLK pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	80	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	—	15	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output invalid	-1.0	—	ns
S7	I2S_TX_BCLK to I2S_TXD valid	—	15	ns
S8	I2S_TX_BCLK to I2S_TXD invalid	0	—	ns
S9	I2S_RXD/I2S_RX_FS input setup before I2S_RX_BCLK	27	—	ns
S10	I2S_RXD/I2S_RX_FS input hold after I2S_RX_BCLK	0	—	ns

**Figure 26. I2S/SAI timing — master modes****Table 45. I2S/SAI slave mode timing in Normal Run, Wait and Stop modes (full voltage range)**

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S11	I2S_TX_BCLK/I2S_RX_BCLK cycle time (input)	80	—	ns

Table continues on the next page...

If you want the drawing for this package	Then use this document number
64-pin LQFP	98ASS23234W
64-pin MAPBGA	98ASA00420D
100-pin LQFP	98ASS23308W
121-pin XFBGA	98ASA00595D

5 Pinout

5.1 K22 Signal Multiplexing and Pin Assignments

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The Port Control Module is responsible for selecting which ALT functionality is available on each pin.

121 BGA	100 LQFP	64 LQFP	64 MAP BGA	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
E4	1	1	A1	PTE0/ CLKOUT32 K	ADC1_ SE4a	ADC1_ SE4a	PTE0/ CLKOUT32 K	SPI1_ PCS1	UART1_TX			I2C1_SDA	RTC_ CLKOUT	
E3	2	2	B1	PTE1/ LLWU_P0	ADC1_ SE5a	ADC1_ SE5a	PTE1/ LLWU_P0	SPI1_ SOUT	UART1_RX			I2C1_SCL	SPI1_SIN	
E2	3	—	—	PTE2/ LLWU_P1	ADC1_ SE6a	ADC1_ SE6a	PTE2/ LLWU_P1	SPI1_SCK	UART1_ CTS_b					
F4	4	—	—	PTE3	ADC1_ SE7a	ADC1_ SE7a	PTE3	SPI1_SIN	UART1_ RTS_b				SPI1_ SOUT	
H7	5	—	—	PTE4/ LLWU_P2	DISABLED		PTE4/ LLWU_P2	SPI1_ PCS0	LPUART0_ TX					
G4	6	—	—	PTE5	DISABLED		PTE5	SPI1_ PCS2	LPUART0_ RX					
F3	7	—	—	PTE6	DISABLED		PTE6	SPI1_ PCS3	LPUART0_ CTS_b	I2S0_ MCLK			USB_SOF_ OUT	
E6	8	3	C5	VDD	VDD	VDD								
G7	9	4	C4	VSS	VSS	VSS								
L6	—	—	—	VSS	VSS	VSS								
F1	10	5	E1	USB0_DP	USB0_DP	USB0_DP								
F2	11	6	D1	USB0_DM	USB0_DM	USB0_DM								
G1	12	7	E2	USBVDD	USBVDD	USBVDD								
G2	13	8	D2	NC	NC	NC								
H1	14	—	—	ADC0_DP1	ADC0_DP1	ADC0_DP1								

121 BGA	100 LQFP	64 LQFP	64 MAP BGA	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
J5	32	—	—	PTE25	ADC0_SE18	ADC0_SE18	PTE25				I2C0_SDA	EWM_IN		
H6	33	—	—	PTE26/ CLKOUT32 K	DISABLED		PTE26/ CLKOUT32 K					RTC_CLKOUT	USB_CLKIN	
J6	34	22	D3	PTA0	JTAG_TCLK/ SWD_CLK/ EZP_CLK		PTA0	UART0_CTS_b	FTM0_CH5				JTAG_TCLK/ SWD_CLK	EZP_CLK
H8	35	23	D4	PTA1	JTAG_TDI/ EZP_DI		PTA1	UART0_RX	FTM0_CH6				JTAG_TDI	EZP_DI
J7	36	24	E5	PTA2	JTAG_TDO/ TRACE_SWO/ EZP_DO		PTA2	UART0_TX	FTM0_CH7				JTAG_TDO/ TRACE_SWO	EZP_DO
H9	37	25	D5	PTA3	JTAG_TMS/ SWD_DIO		PTA3	UART0_RTS_b	FTM0_CH0				JTAG_TMS/ SWD_DIO	
J8	38	26	G5	PTA4/ LLWU_P3	NMI_b/ EZP_CS_b		PTA4/ LLWU_P3		FTM0_CH1				NMI_b	EZP_CS_b
K7	39	27	F5	PTA5	DISABLED		PTA5	USB_CLKIN	FTM0_CH2				I2S0_TX_BCLK	JTAG_TRST_b
E5	40	—	—	VDD	VDD	VDD								
G3	41	—	—	VSS	VSS	VSS								
K8	42	28	H6	PTA12	DISABLED		PTA12		FTM1_CH0				I2S0_TXD0	FTM1_QD_PHA
L8	43	29	G6	PTA13/ LLWU_P4	DISABLED		PTA13/ LLWU_P4		FTM1_CH1				I2S0_TX_FS	FTM1_QD_PHB
K9	44	—	—	PTA14	DISABLED		PTA14	SPI0_PCS0	UART0_TX				I2S0_RX_BCLK	
L9	45	—	—	PTA15	DISABLED		PTA15	SPI0_SCK	UART0_RX				I2S0_RXD0	
J10	46	—	—	PTA16	DISABLED		PTA16	SPI0_SOUT	UART0_CTS_b				I2S0_RX_FS	
H10	47	—	—	PTA17	ADC1_SE17	ADC1_SE17	PTA17	SPI0_SIN	UART0_RTS_b				I2S0_MCLK	
L10	48	30	G7	VDD	VDD	VDD								
K10	49	31	H7	VSS	VSS	VSS								
L11	50	32	H8	PTA18	EXTAL0	EXTAL0	PTA18		FTM0_FLT2	FTM_CLKIN0				
K11	51	33	G8	PTA19	XTAL0	XTAL0	PTA19		FTM1_FLT0	FTM_CLKIN1			LPTMR0_ALT1	
J11	52	34	F8	RESET_b	RESET_b	RESET_b								
G11	53	35	F7	PTB0/ LLWU_P5	ADC0_SE8/ ADC1_SE8	ADC0_SE8/ ADC1_SE8	PTB0/ LLWU_P5	I2C0_SCL	FTM1_CH0				FTM1_QD_PHA	

Pinout

121 BGA	100 LQFP	64 LQFP	64 MAP BGA	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
K3	—	—	—	NC	NC	NC								
H4	—	—	—	NC	NC	NC								
B11	—	—	—	NC	NC	NC								
C11	—	—	—	NC	NC	NC								
H11	—	—	—	NC	NC	NC								
C1	—	—	—	NC	NC	NC								
D2	—	—	—	NC	NC	NC								
D1	—	—	—	NC	NC	NC								
E1	—	—	—	NC	NC	NC								
J3	—	—	—	NC	NC	NC								
H3	—	—	—	NC	NC	NC								
J9	—	—	—	NC	NC	NC								
J4	—	—	—	NC	NC	NC								
A10	—	—	—	NC	NC	NC								
A9	—	—	—	NC	NC	NC								
B1	—	—	—	NC	NC	NC								
C2	—	—	—	NC	NC	NC								
L7	—	—	—	NC	NC	NC								
F11	—	—	—	NC	NC	NC								
E11	—	—	—	NC	NC	NC								
A4	—	—	—	NC	NC	NC								

5.2 Recommended connection for unused analog and digital pins

The following table shows the recommended connections for analog interface pins if those analog interfaces are not used in the customer's application.

Table 48. Recommended connection for unused analog interfaces

Pin Type		Short recommendation	Detailed recommendation
Analog/non GPIO	PGAx/ADCx	Float	Analog input - Float
Analog/non GPIO	ADCx/CMPx	Float	Analog input - Float
Analog/non GPIO	VREF_OUT	Float	Analog output - Float
Analog/non GPIO	DACx_OUT	Float	Analog output - Float
Analog/non GPIO	RTC_WAKEUP_B	Float	Analog output - Float
Analog/non GPIO	XTAL32	Float	Analog output - Float
Analog/non GPIO	EXTAL32	Float	Analog input - Float

Table continues on the next page...

Pinout

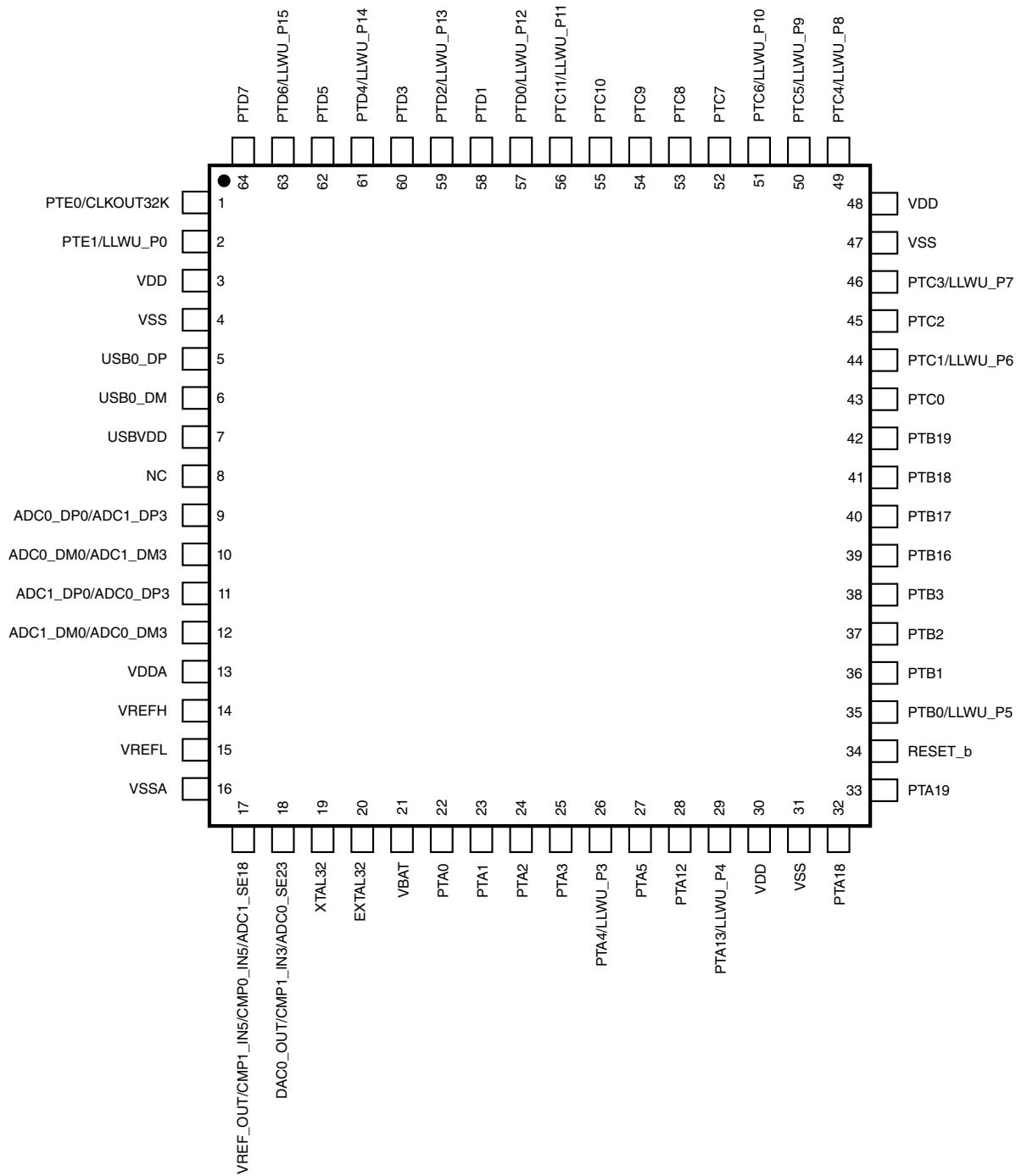


Figure 30. K22 64 LQFP Pinout Diagram (top view)

6.4 Example

This is an example part number:

MK22FN128VDC10

6.5 121-pin XFBGA part marking

The 121-pin XFBGA package parts follow the part-marking scheme in the following table.

Table 49. 121-pin XFBGA part marking

MK Partnumber	MK Part Marking
MK22FN128VDC10	M22J7VDC

6.6 64-pin MAPBGA part marking

The 64-pin MAPBGA package parts follow the part-marking scheme in the following table.

Table 50. 64-pin MAPBGA part marking

MK Partnumber	MK Part Marking
MK22FN128VMP10	M22J7V

7 Terminology and guidelines

7.1 Definitions

Key terms are defined in the following table:

Term	Definition
Rating	A minimum or maximum value of a technical characteristic that, if exceeded, may cause permanent chip failure: <ul style="list-style-type: none"> • <i>Operating ratings</i> apply during operation of the chip. • <i>Handling ratings</i> apply when the chip is not powered.

Table continues on the next page...

Revision History

Table 51. Revision History

Rev. No.	Date	Substantial Changes
7	08/2016	<ul style="list-style-type: none"> Added Terminology and Guidelines section Updated the front matter section Added Device Revision Number Table Updated Chip Errata naming convention in Related Resource table
6	10/2015	<ul style="list-style-type: none"> In "Power consumption operating behaviors" section, added "Low power mode peripheral adders—typical value" table In "Thermal operating requirements" table, in footnote, corrected "$T_J = T_A + \Theta_{JA}$" to "$T_J = T_A + R_{\Theta JA}$" Updated "IRC48M specifications" table Updated "NVM program/erase timing specifications" table; updated values for $t_{hversall}$ (Erase All high-voltage time) In "Slave mode DSPI timing (limited voltage range)" table, added footnote regarding maximum frequency of operation Added new section, "Recommended connections for unused analog and digital pins"
5	4/2015	<ul style="list-style-type: none"> On page 1: <ul style="list-style-type: none"> In first bullet of introduction, updated power consumption data to align with the data in the "Power consumption operating behaviors" table In second bullet of introduction, added "USB FS device crystal-less functionality" Under "Communication interfaces," updated I²C bullet to indicate support for up to 1 Mbps operation Under "Operating characteristics," specified that voltage range includes flash writes In "Voltage and current operating requirements" table: <ul style="list-style-type: none"> Removed content related to positive injection Updated footnote 1 to say that all analog and I/O pins are internally clamped to V_{SS} only (not V_{SS} and V_{DD}) through ESD protection diodes. In "Power consumption operating behaviors" table: <ul style="list-style-type: none"> Added additional temperature data in power consumption table Added Max IDD values based on characterization results equivalent to mean + 3 sigma Updated "EMC radiated emissions operating behaviors" table In "Thermal operating requirements" table, added the following footnote for ambient temperature: "Maximum T_A can be exceeded only if the user ensures that T_J does not exceed maximum T_J. The simplest method to determine T_J is: T_J = T_A + Θ_{JA} x chip power dissipation" Updated "IRC48M Specifications": <ul style="list-style-type: none"> Updated maximum values for Δ_{firc48m.ol.lv} and Δ_{firc48m.ol.hv} (full temperature) Added specifications for Δ_{firc48m.ol.hv} (-40°C to 85°C) Updated notes in "USB electrical specifications" section In "I²C timing" table, <ul style="list-style-type: none"> Added the following footnote on maximum Fast mode value for SCL Clock Frequency: "The maximum SCL Clock Frequency in Fast mode with maximum bus loading can only be achieved when using the High drive pins across the full voltage range and when using the Normal drive pins and V_{DD} ≥ 2.7 V." Updated minimum Fast mode value for LOW period of the SCL clock to 1.25 μ Added "I²C 1 Mbps timing" table Specified that the figure, "K22F 64 LQFP Pinout Diagram" is a top view Specified that the figure, "K22F 64 MAPBGA Pinout Diagram" is a transparent top view Specified that the figure, "K22F 100 LQFP Pinout Diagram" is a top view

Table continues on the next page...